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	INFO	RMATION DISCLOSURE (Use several sheets if necessa	Applicant(s) Noriyuki MIURA							
					Filing Date December 9, 20	Group Art Unit To Ro Assigned				
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*EXAMINER	U.S. PATENT DOCUMENTS EXAMINER DEE DOCUMENT NUMBER DATE NAME CLASS SUBCLASS FILING DATE									
INITIAL	REF	DOCUMENT NUMBER	DATE	 	NAME*	CLASS	SUBCLASS	IF APPRO		
1.4.	A	6,093,592	07/25/2000	NAKAB	BAYASHI et al.	438	221			
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1.7:	В	63-313865	12/21/1988	JAPAN				Abstract		
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Lisa T. Su et al., "OPTIMIZATION OF SERIES RESISTANCE IN SUB-0.2 µm SOI MOSFETs", 1993 IEEE, pgs. 723-726.										
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EXAMINER of Later Considered 12/9/04										
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										

Form PTO-A820 (also form PTO-1449)